

A new era of pixel detectors for future High Energy Physics experiments

Sonia Fernandez-Perez

Workshop física teorica UVA-27.05.2016



Outline



- The Large Hadron Collider (LHC)
- The ATLAS detector
- The HL- LHC program
- Basic working principle and challenges of pixel detectors
- Pixel detectors developments for ATLAS at HL-LHC



- The Standard Model describes all elementary particles and their interactions
- It is incomplete (no explanation to gravitational interactions, dark matter, asymmetry matter-antimatter, etc)





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- proton-proton collider
- 27 km circumference
- 100 m underground
- During the first data taking period Run 1 (2009-2012) luminosity of 10³⁴ cm⁻²s⁻¹, collision energy of 7-8 TeV, and 50 ns bunch crossing.
- 4 main experiments: ALICE, ATLAS, CMS, LHCb



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CERI





Introduction The ATLAS detector





Introduction The Pixel Detector





- The Pixel Detector is exposed to the harshest conditions
 - 4 silicon detector layers





Introduction The Pixel Detector





Insertable B-Layer (IBL) installed in 2014



• 4 silicon detector layers

A true 4-hit pixel system!





Introduction The Pixel Detector





- The Pixel Detector is exposed to the harshest conditions
- 4 silicon detector layers
- Each layer is composed of
 2D segmented silicon detectors







- Layers of segmented silicon detectors
- The energy loss by the particle while traversing the detector \rightarrow electrical signal





FAE

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- The energy loss by the particle while traversing the detector \rightarrow electrical signal





IFAE⁹

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• pixel sensor: a 2D segmented pn-diode (reversely bias \rightarrow depletion zone)







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- Depletion zone is the zone without free charge carriers







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LHC pixel detectors





CÉRN

Introduction High Luminosity LHC



• Why do we need high luminosity?

frequency to obtain an specific event:

$$\begin{split} \mathbf{N}_{\text{event}} &= \text{Luminosity } \times \boldsymbol{\sigma}_{\text{event}} \\ \sigma \; (\text{pp}) &= \; 10^{11} \; \text{pb} \\ \sigma \; (\text{W/Z}) &= \; 10^4 \; \text{pb} \\ \sigma \; (\text{H}) &= \; 100 \; \text{pb} \end{split}$$





Introduction High Luminosity LHC



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• The LHC plans to increase by a factor of 7 the luminosity in 2026 \rightarrow HL-LHC program



[luminosity of 7* 10³⁴ cm⁻²s⁻¹, collision energy of 14 TeV, and 25 ns bunch crossing]



Detector implications:

- Radiation hard detectors
- High rate
- Fast detectors



- The full Inner Detector of ATLAS will be replaced by a new all-silicon detector
 - Pixels and Strips
- The Pixel Detector layout is under discussion (4-6 layers)
- The requirements are at least one order of magnitude higher





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	Pixels LHC	IBL	Pixels HL-LHC	Pixels HL-LHC
			(inner layers)	(outer layers)
Particle rate	1 MHz/mm ²	5 MHz/mm ²	$10 \mathrm{MHz/mm^2}$	1 MHz/mm ²
Total Ionizing Dose (TID)	50 Mrad	250 Mrad	1 Grad	50 Mrad
Non Ionizing Energy Loss (NIEL)	$10^{15} n_{eq} cm^{-2}$	$5 \times 10^{15} n_{eq} \text{cm}^{-2}$	$2 \times 10^{16} n_{eq} cm^{-2}$	$1 \times 10^{15} n_{eq} \text{cm}^{-2}$
Silicon Area	$\approx 1.73 \mathrm{m}^2$	$\approx 0.15 \mathrm{m}^2$	$\approx 1 \text{ m}^2$	$\approx 10 - 20 \mathrm{m}^2$
Pile-up	23	23	200	-





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Hybrid technologyHybrid technologyPlanar Pixel Sensor (PPS)Planar Pixel Sensor (PPS)3D Silicon sensor (3D)





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Inner layers

- 1. Radiation hardness
- 2. Low power consumption
- 3. Low material
- 4. Occupancy





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Inner layers

Outer layers

- **1.** Radiation hardness
- 1. time schedule

Low material

- 2. Low power consumption 2. Low cost
- 3. Low material

3. Low power consumption



4. Occupancy **4.** Workshop física teórica UVA - Sonia Fernandez-Perez



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Pixel developments for ATLAS at HL-LHC. From Hybrid detectors to depleted Monolithic detectors







Hybrid pixels

- Sensor + front-end chip separated entities
- Signal collected by drift
- Mature technology (in use since LEP 1996)



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Hybrid pixels

- Sensor + front-end chip separated entities
- Signal collected by drift
- Mature technology (in use since LEP 1996)

Advantages

- Complex signal processing already in pixel cell possible
 - zero suppression, temporary storage of hits during L1 latency
- Radiation hard to > $10^{15} n_{eq}/cm^2$
- High rate capability (~MHz/mm²)



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Disadvantages

- Complex and laborious module production
 - Many production steps ightarrow low production yield
 - Bump-bonding / flip-chipping → limiting pixel size
 - Expensive
- Relatively large material budget ~3% X_o per layer
 - sensor + chip + flex kapton + passive components
 - support, cooling, services





© T. Hemperek, Bonn, DE







Planar Pixel Sensor (PPS)

- Technology used in present Pixel Detector
- Collection distance = drift distance
- High production yield (%)
 - Large area sensors





Hybrid sensors technologies





Planar Pixel Sensor (PPS)

- Technology used in present Pixel Detector
- Collection distance = drift distance
- High production yield (%)
 - Large area sensors

3D Silicon Sensor (3D)

- Technology installed for the first time IBL
- Collection- and drift distance disconnected
- More difficult production, lower yield
 - Smaller area sensors









CMOS-based pixels

- Industrial process
 - higher production yield
 - cheaper sensors
- Collecting electrode inside →logic implementation in same silicon tile
 → capacitive coupled connections, monolithic ...
 - smaller cost
 - smaller material budget
 - smaller pixel size
- There are two approaches

$$W = \sqrt{2 \epsilon \, \mu \rho V_b}$$



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plate	U	V I	→ ∐
Sec. 1			
Pixel CMOS sensor			

• Both technologies are developed so far as hybrid approach







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- Complex R/O electronics in sensor layer needed.
- High resistivity epitaxial layer
- Slow charge collection (diffusion)
- "low" radiation hardness
- STAR (2014), ALICE ITS (2018)









ALICE ITS (L. Mussa)

STAR / RHIC



needed.



Complex R/O electronics in sensor layer

High resistivity epitaxial layer

STAR (2014), ALICE ITS (2018)

"low" radiation hardness

Slow charge collection (diffusion)



in operation since 2014









ALICE ITS (L. Mussa)

Depleted MAPS



- Complex R/O electronics in sensor layer needed.
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- Complex R/O electronics in sensor layer needed.
- High voltage/high resistivity process
- Fast charge collection (drift)
- [BELLE II DEPFET]









ALICE ITS (L. Mussa)

CERM

Depleted MAPS



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Belle II (SuperKEK) DEPFET



in production for 2017

Depleted Monolithic Active Pixel Sensors



Depleted MAPS Silicon-On-Insulator



★┣₽
Diode + Amp + Digital

- Silicon-On-Insulator to separate logic from sensor diode. Several advantages:
 - Decoupling of electronics and sensor silicon resistivity
 - No competing NWELL
 - Free choice of fill factor
 - Lower cross-talk
- Charge collection by drift





Depleted MAPS Silicon-On-Insulator





Standard

- Distance transistors-BOX ~nm
- Ultra-thin transistor body ~O(40 nm) FD
- Radiation hardness very challenging
- OKI/LAPIS

Thick film

- Distance transistors-BOX ~μm
- Thick transistor body PD
- Multiple "wells" structures





Summary of pixel developments features



	Hybrid	CMOS pixels	Monolithic CMOS
Examples	3D, Planar (ATLAS, CMS, LHCvelo,Timepix3)	HV-CMOS HR-CMOS	MAPS (STAR, ALICE ITS) DMAPS SOI
Technology	Industry standard for readout; special high-Ω sensors	R/O and sensors integrated, close to industrial process	R/O and sensor in same piece of silicon; Industrial process
Interconnection	Bump-bonding required	Connectivity facilitated (CCPD) (or monolithic approach)	No needed
Granularity	50 μm x 50 μm	Down to few-micron sizes	Down to few-micron sizes
Timing	Fast	Coarse but improving	Coarse but improving
Radiation hardness	Feasible	To be proven	To be proven







R/O chip



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Diode +

Preamp

Sensor

R/O chip

R/O chip

Summary of pixel developments features

Sensor

R/O chip



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CERN	★		

Preamp

http://visits.web.cern.ch









http://jobs.web.cern.ch









Thank for your attention





Spare slides





AD Antiproton Decelerator CTF-3 Clic Test Facility CNC5 Cern Neutrinos to Gran Sesso ISOLDE Isotope Separator ChLine Devon

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[Slide by N. Wermes, Elba 2015]

	BX time	Particle Rate	NIEL Fluence	lon. Dose
	ns	kHz/mm ²	n _{eq} /cm² per lifetime*	Mrad per lifetime*
LHC (10 ³⁴ cm ⁻² s ⁻¹)	25	1000	2×10 ¹⁵	79
HL-LHC (10³⁵ cm ²s ⁻¹)	25	10000	2×10 ¹⁶	> 500
tHC Heavy lons (6×10 ²⁷ cm ⁻² s ⁻¹)	20.000	10	>1013	0.7
RHIC (8×10 ²⁷ cm ⁻² s ⁻¹)	110	3.8	few 10 ¹²	0.2
SuperKEKB (10 ³⁵ cm ⁻² s ⁻¹)	2	400	~3 x 10 ¹²	10
ILC (10 ³⁴ cm ⁻² s ⁻¹)	350	250	1012	0.4
Monolithic Pixels	ower rates ower radiatio maller pixels ess material petter resolut	DEPFET: Bell MAPS: STAR and f ALICE	le II @RHIC uture E ITS	assumed lifetimes: LHC, HL-LHC: 7 years LC: 10 years others: 5 years





The 4 listed projects have many individual requirements in common, though their combination is different

- Layers of segmented silicon detectors
- The energy loss by the particle while traversing the detector \rightarrow electrical signal
- The loss of energy by charged particles in matter ightarrow inelastic collisions

Charged particles (m >> m_e)

- Excitation and ionization of atoms
- Part of the energy is transferred to the atom
- Bethe-Bloch formula

Charged particles (m ~ m_e)

- Ionization of atoms + other
- At high energies → Bremsstrahlung dominates







Transverse momentum resolution

$$\frac{\sigma_{p_T}}{p_T} = \sqrt{\left(\frac{\sigma_{p_T}}{p_T}\right)^2_{point} + \left(\frac{\sigma_{p_T}}{p_T}\right)^2_{MS}}$$

$$\frac{\sigma_{p_T}}{p_T}_{point} = p_T \cdot \frac{\sigma}{0.3BL^2} \cdot \sqrt{\frac{720N^3}{(N-1)(N+1)(N+2)(N+3)}}$$
$$\frac{\sigma_{p_T}}{p_T}_{MS} = \frac{1}{0.3B} \frac{0.0136}{\beta} \sqrt{\frac{C_N}{X_0L}}$$

Vertex and Impact Parameter resolution

$$\sigma_{vtx}^2 \sim \frac{r_1^2 \sigma_1^2 + r_2^2 \sigma_2^2}{(r_2 - r_1)^2} + \frac{(2r_1 r_2 - r_0 (r_1 + r_2))^2}{(r_2 - r_1)^2} \cdot \left(\frac{13.6 \,\mathrm{MeV}}{pv} \cdot \sqrt{\frac{d}{X_o}}\right)^2$$
$$\sigma_{d_0} = \sqrt{\frac{\sigma^2}{(N+1)} + \frac{\sigma^2}{(N+1)} \frac{12N}{(N+2)} \frac{z_c^2}{L^2}}; \qquad z_c = (z_N - z_0)/2$$





- large detector coverage in η
- a trade off between the material budget and the number of tracking layers
- location of the first layer as close as possible to the interaction point
- high magnetic field
- small detector and beam pipe thickness
- fine detector segmentation, specially in the layers close to the interaction point
- detector radiation hardness up to the expected fluences
- excellent detector efficiency which ensures a measurement point per detector layer
- high readout speed (25 ns in-time)



CMOS Pixel Technologies



HV-CMOS



- HV technology (100V)
- Logic in-sensor
- Two approaches
 - Bump-bonded to dedicated R/O chip
 - Capacitive coupling via isolating glue
- Proven up to
 - 1GRad TID, 10¹⁵ n_{eq}cm⁻²
 - 99% (96%) efficiency before (after) irr
 - depletion depth 10-20µm at 100V
 - signal rise-time 100ns
- A HV-CMOS prototype in 350nm produced in large scale (2x2cm)



- High resistivity substrate (1-2 KΩ cm)
- Two variants are being investigated
 - different geometries
- Two approaches
 - Bump-bonded to dedicated R/O chip
 - Monolithic
- Proven up to
 - Depletion 60μm at 20V (6200e⁻)
 - Rise-time within 25ns (threshold dependency)
- A HR-CMOS prototype in 150nm selected
 - \rightarrow production in large scale (2x2cm)



XTB01 prototype





- 2 x 5 mm²
- 300 μm thick
- 4 metal layers, wafer size: 8"
- Four matrices with different pixel sizes (25x25 μm², 50x50 μm², 100x100 μm²)
- Transistor test structures
- HV ring, grid rings, n-rings



- thick film DMAPS SOI
 0.18 μm
- BOX isolates sensor and electronics
- thick film, double PWELL
- no back-processing (HV applied from front side)
- MIP detection